

## 120V N-Channel Enhancement Mode MOSFET

### Description

The AP90N12D uses advanced **SGT II** technology to provide excellent  $R_{DS(ON)}$ , low gate charge and operation with gate voltages as low as 7.5V. This device is suitable for use as a Battery protection or in other Switching application.

### General Features

$V_{DS} = 120V$   $I_D = 90A$

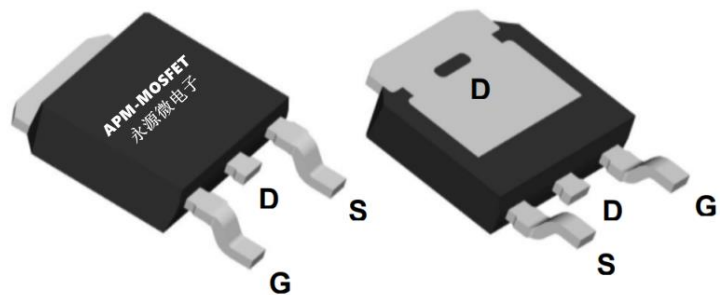
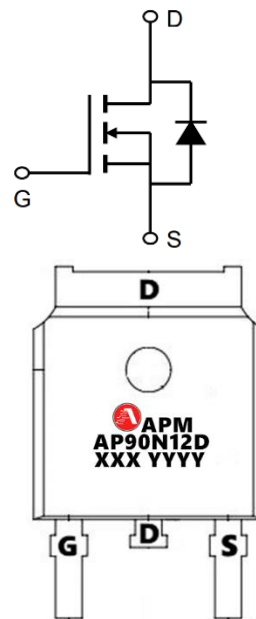
$R_{DS(ON)} < 9.0m\Omega$  @  $V_{GS}=10V$  (**Type: 7.5mΩ**)

### Application

Mobile phone fast charging

Brushless motor

Home appliance control board



### Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
AP90N12D	TO-252-3L	AP90N12D XXXX YYYY	2500

### Absolute Maximum Ratings ( $T_C=25^{\circ}C$ unless otherwise noted)

Symbol	Parameter	Value	Unit
$V_{DS}$	Drain source voltage	120	V
$V_{GS}$	Gate source voltage	$\pm 20$	V
$I_D@T_A=25^{\circ}C$	Continuous drain current <sup>1)</sup> , $T_C=25^{\circ}C$	90	A
$I_D@T_A=70^{\circ}C$	Continuous drain current <sup>1)</sup> , $T_C=75^{\circ}C$	35	A
$I_{DM}$	Pulsed drain current <sup>2)</sup> , $T_C=25^{\circ}C$	270	A
$P_D$	Power dissipation <sup>3)</sup> , $T_C=25^{\circ}C$	160	W
EAS	Single pulsed avalanche energy <sup>4)</sup>	125	mJ
$T_{stg}, T_j$	Operation and storage temperature	-55 to 150	$^{\circ}C$
$R_{\theta JC}$	Thermal resistance, junction-case	0.89	$^{\circ}C/W$
$R_{\theta JA}$	Thermal resistance, junction-ambient <sup>5)</sup>	62.5	$^{\circ}C/W$



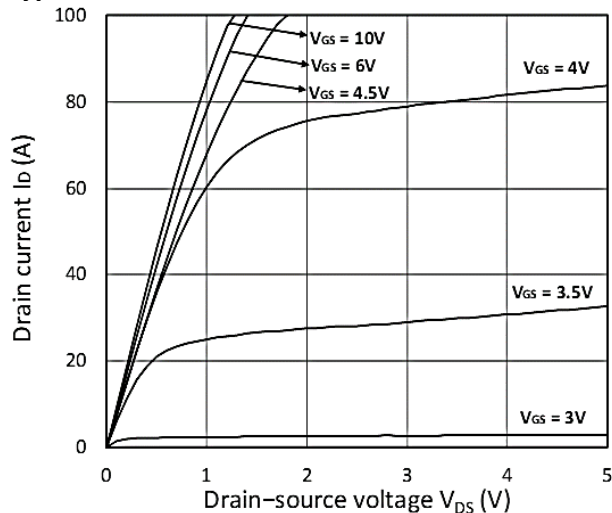
**120V N-Channel Enhancement Mode MOSFET**
**Electrical Characteristics ( $T_J=25^{\circ}\text{C}$ , unless otherwise noted)**

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
V(BR)DSS	Drain-Source Breakdown Voltage	$V_{GS} = 0V, I_D = 250\mu A$	120	135	-	V
IGSS	Gate-body Leakage current	$V_{DS} = 0V, V_{GS} = \pm 20V$	-	-	$\pm 100$	nA
IDSS $T_J=25^{\circ}\text{C}$	Zero Gate Voltage Drain Current	$V_{DS} = 120V, V_{GS} = 0V$	-	-	1	$\mu A$
IDSS $T_J=100^{\circ}\text{C}$			-	-	100	
VGS(th)	Gate-Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250\mu A$	1.5	2.0	2.5	V
RDS(on)	Drain-Source on-Resistance <sup>4</sup>	$V_{GS} = 10V, I_D = 20A$	-	7.5	9.0	m $\Omega$
		$V_{GS} = 4.5V, I_D = 10A$	-	9.0	12	
gfs	Forward Transconductance <sup>4</sup>	$V_{DS}=10V, I_D=20A$	-	75	-	S
Ciss	Input Capacitance	$V_{DS} = 60V, V_{GS} = 0V, f = 1MHz$	-	1854	-	pF
Coss	Output Capacitance		-	270	-	
Crss	Reverse Transfer Capacitance		-	10	-	
Rg	Gate Resistance	$f = 1MHz$	-	2.3	-	$\Omega$
Qg	Total Gate Charge	$V_{GS} = 10V, V_{DS} = 60V, I_D = 20A$	-	30	-	nC
Qgs	Gate-Source Charge		-	5.8	-	
Qgd	Gate-Drain Charge		-	6	-	
td(on)	Turn-on Delay Time	$V_{GS} = 10V, V_{DD} = 60V, R_G = 3\Omega, I_D = 20A$	-	9.5	-	ns
tr	Rise Time		-	4.2	-	
td(off)	Turn-off Delay Time		-	27.2	-	
tf	Fall Time		-	6.6	-	
trr	Body Diode Reverse Recovery Time	$I_F = 20A, dI/dt = 100A/\mu s$	-	52	-	ns
Qrr	Body Diode Reverse Recovery Charge		-	83.5	-	nC
VSD	Diode Forward Voltage <sup>4</sup>	$I_S = 20A, V_{GS} = 0V$	-	-	1.2	V
IS $T_C=25^{\circ}\text{C}$	Continuous Source Current	-	-	-	90	A

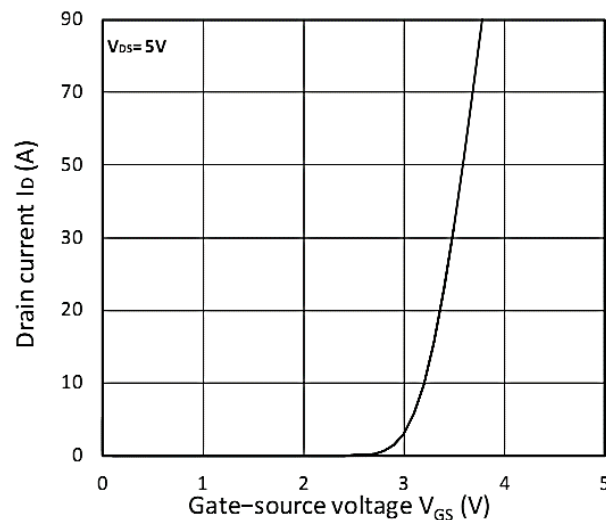
**Note :**

- 1、The data tested by surface mounted on a 1 inch 2 FR-4 board with 2OZ copper.
- 2、The data tested by pulsed , pulse width .The EAS data shows Max. rating .
- 3、The power dissipation is limited by  $175^{\circ}\text{C}$  junction temperature
- 4、EAS condition:  $T_J=25^{\circ}\text{C}$ ,  $V_{DD}=50V, V_{GS}=10V, L=0.1mH$ ,  $I_{AS}=30A$
- 5、The data is theoretically the same as ID and IDM , in real applications , should be limited by total power dissipation.

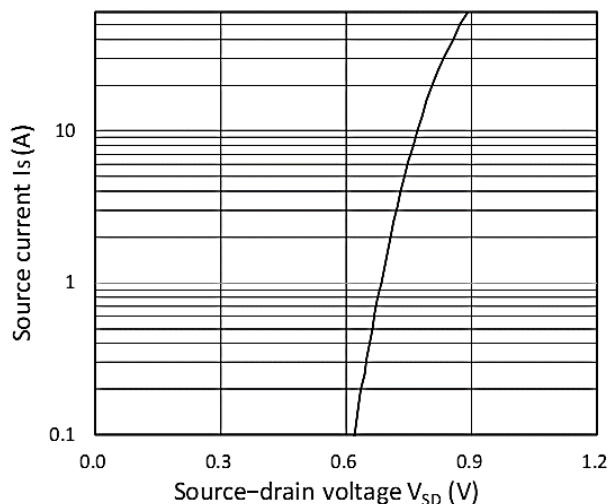
**Typical Characteristics**



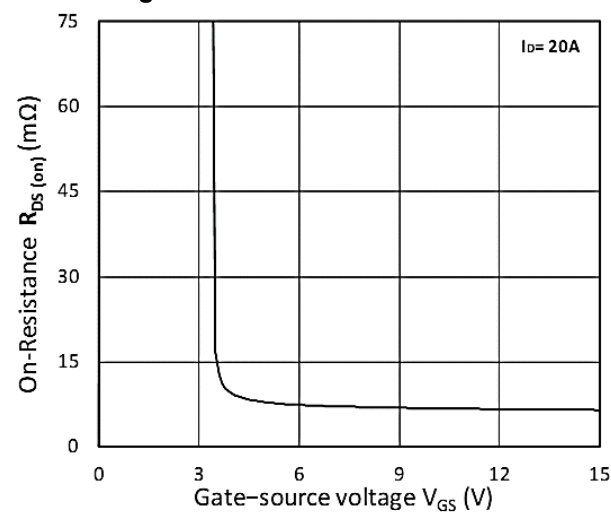
**Figure 1. Output Characteristics**



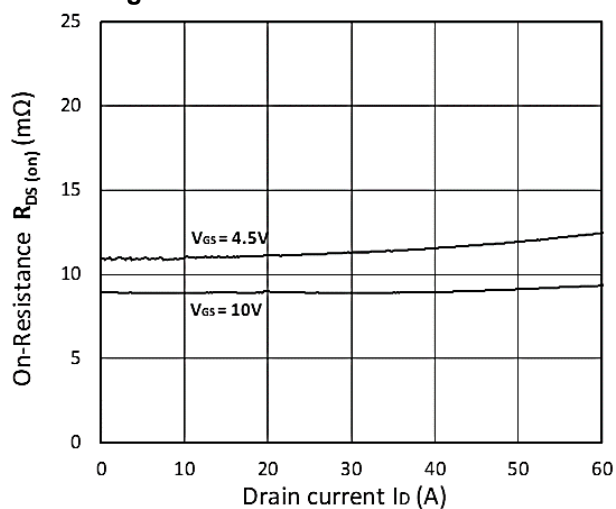
**Figure 2. Transfer Characteristics**



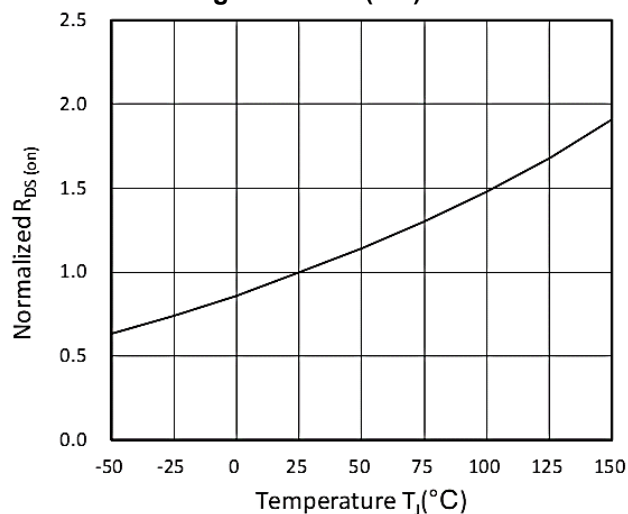
**Figure 3. Forward Characteristics of Reverse**



**Figure 4.  $R_{DS(ON)}$  vs.  $V_{GS}$**

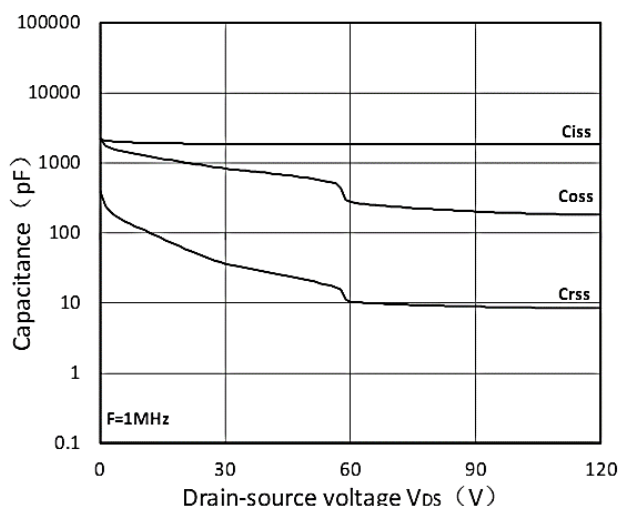


**Figure 5.  $R_{DS(ON)}$  vs.  $I_D$**

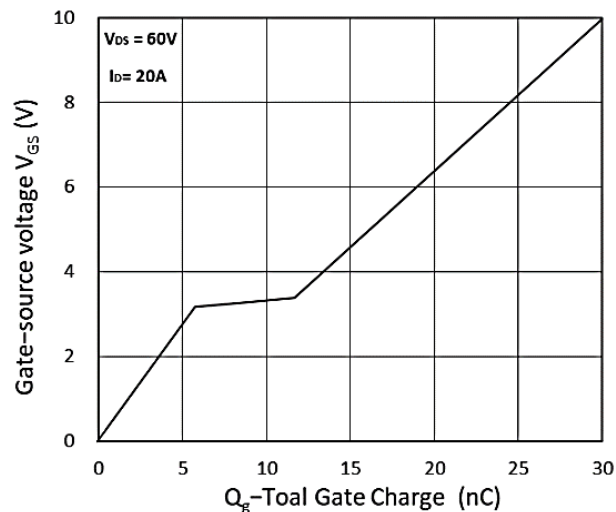


**Figure 6. Normalized  $R_{DS(on)}$  vs. Temperature**

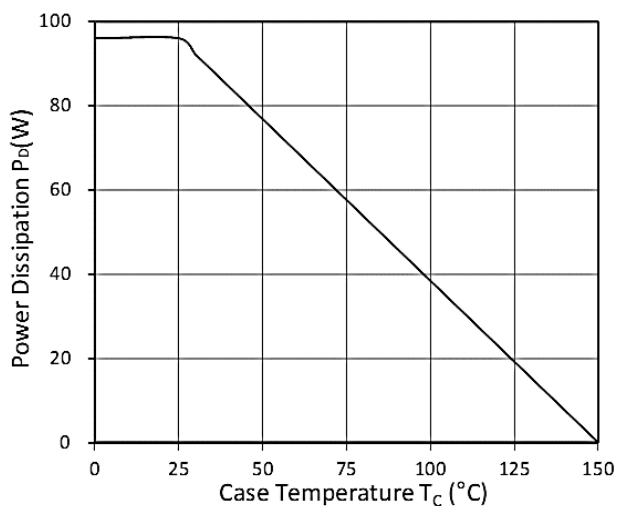
**120V N-Channel Enhancement Mode MOSFET**



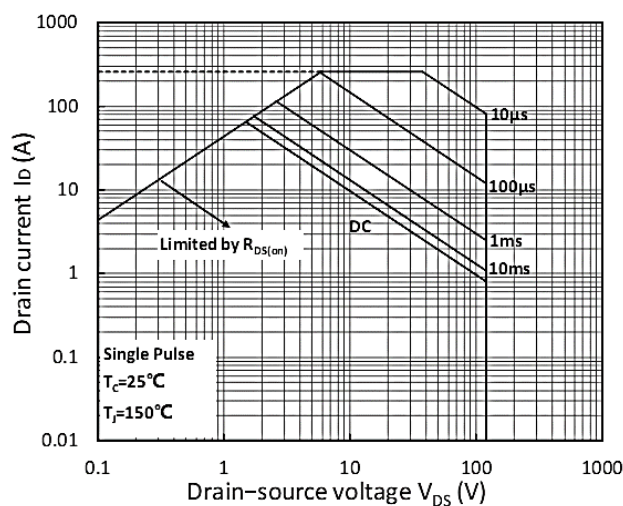
**Figure 7. Capacitance Characteristics**



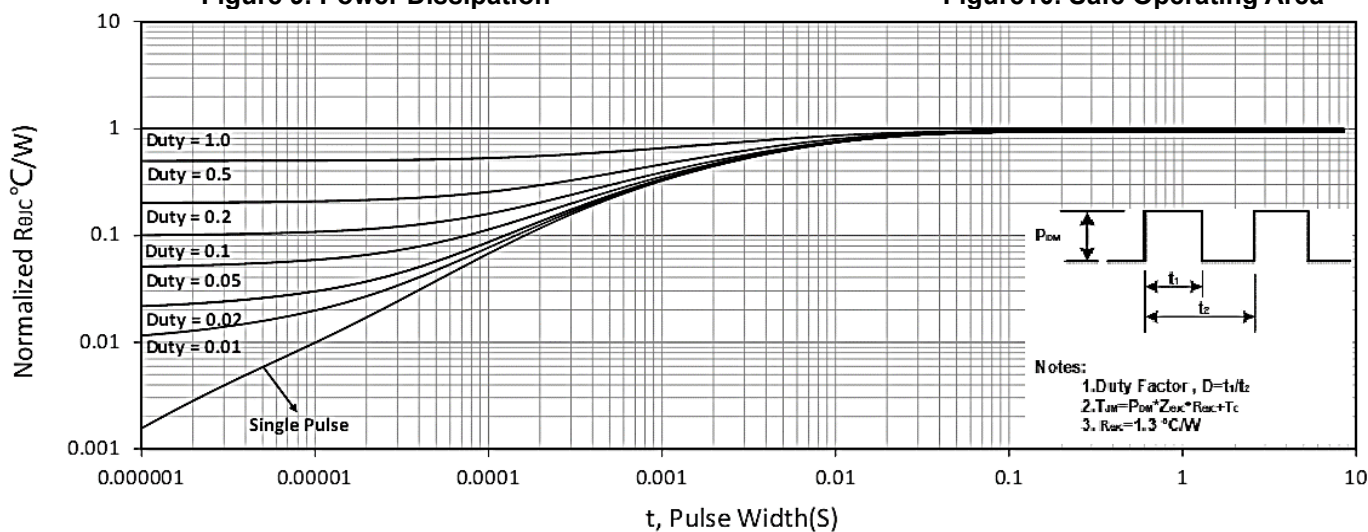
**Figure 8. Gate Charge Characteristics**



**Figure 9. Power Dissipation**

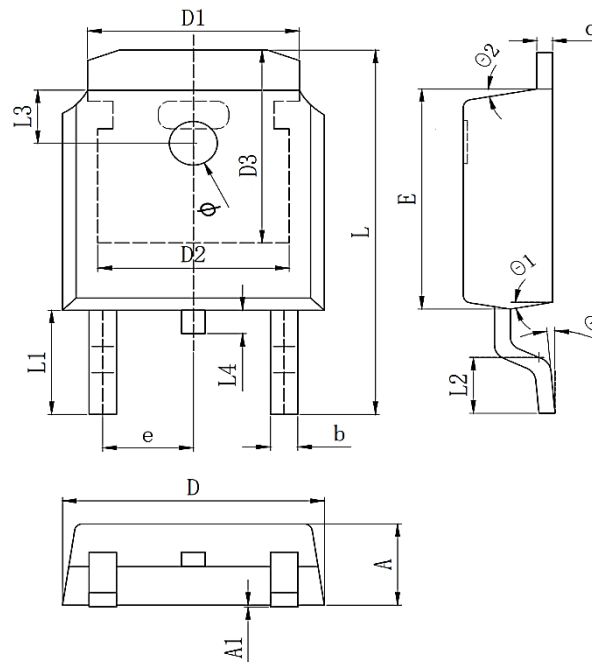


**Figure 10. Safe Operating Area**



**Figure 11. Normalized Maximum Transient Thermal Impedance**

**Package Mechanical Data-TO-252-3L**



Symbol	Dim in mm		
	Min	Typ	Max
A	2.1	2.3	2.5
A1	0	0.064	0.128
b	0.64	0.75	0.86
c	0.45	0.52	0.6
D	6.4	6.6	6.8
D1	5.33REF		
D2	4.83REF		
D3	5.25REF		
E	5.9	6.1	6.3
e	2.286TYP		
L	9.8	10.1	10.4
L1	2.888REF		
L2	1.4	1.5	1.7
L3	1.65REF		
L4	0.6	0.8	1
φ	1.1	1.2	1.3
θ	0°		10°
θ1	5°		10°
θ2	5°		10°

### Attention

1, Any and all APM Microelectronics products described or contained herein do not have specifications that can handle applications that require extremely high levels of reliability, such as life support systems, aircraft's control systems, or other applications whose failure can be reasonably expected to result in serious physical and/or material damage. Consult with your APM Microelectronics representative nearest you before using any APM Microelectronics products described or contained herein in such applications.

2, APM Microelectronics assumes no responsibility for equipment failures that result from using products at values that exceed, even momentarily, rated values (such as maximum ratings, operating condition ranges, or other parameters) listed in products specifications of any and all APM Microelectronics products described or contained herein.

3, Specifications of any and all APM Microelectronics products described or contained here instipulate the performance, characteristics, and functions of the described products in the independent state, and are not guarantees of the performance, characteristics, and functions of the described products as mounted in the customer's products or equipment. To verify symptoms and states that cannot be evaluated in an independent device, the customer should always evaluate and test devices mounted in the customer's products or equipment.

4, APM Microelectronics Semiconductor CO., LTD. strives to supply high quality high reliability products. However, any and all semiconductor products fail with some probability. It is possible that these probabilistic failures could give rise to accidents or events that could endanger human lives that could give rise to smoke or fire, or that could cause damage to other property. When designing equipment, adopt safety measures so that these kinds of accidents or events cannot occur. Such measures include but are not limited to protective circuits and error prevention circuits for safe design, redundant design, and structural design.

5, In the event that any or all APM Microelectronics products (including technical data, services) described or contained herein are controlled under any of applicable local export control laws and regulations, such products must not be exported without obtaining the export license from the authorities concerned in accordance with the above law.

6, No part of this publication may be reproduced or transmitted in any form or by any means, electronic or mechanical, including photocopying and recording, or any information storage or retrieval system, or otherwise, without the prior written permission of APM Microelectronics Semiconductor CO., LTD.

7, Information (including circuit diagrams and circuit parameters) herein is for example only; it is not guaranteed for volume production. APM Microelectronics believes information herein is accurate and reliable, but no guarantees are made or implied regarding its use or any infringements of intellectual property rights or other rights of third parties.

8, Any and all information described or contained herein are subject to change without notice due to product/technology improvement, etc. When designing equipment, refer to the "Delivery Specification" for the APM Microelectronics product that you intend to use.

Edition	Date	Change
REV1.0	2023/8/1	Initial release

Copyright Attribution“APM-Microelectronice”